

---

## JEI Letters



**Jan P. Allebach**  
Editor-in-Chief

We have added a new section to the *Journal of Electronic Imaging* called JEI Letters. The purpose of this section is to provide rapid publication of short technical communications of significant interest in the field of electronic imaging.

Submissions will be reviewed with the same rigor as regular journal articles but with an accelerated pace. The manuscript length may not exceed three printed journal pages. A brief cover letter setting forth the significance of the paper must accompany the manuscript, outlining why the paper merits rapid publication. Accepted manuscripts will be scheduled for publication in the next available issue, and the publication process will be expedited so that the letters will be published as rapidly as possible. Using the technology of JEI's new e-First publication process, each article will appear online as soon as the author proof cor-

rections have been incorporated, without waiting for the rest of the papers in that issue to be finalized.

All articles that appear in JEI Letters will also be linked to the upcoming new *SPIE Letters* virtual journal. This virtual journal will be an online compilation of links to letters published in each of SPIE's four journals: *Optical Engineering*, the *Journal of Biomedical Optics*, the *Journal of Microlithography, Microfabrication, and Microsystems* (JM<sup>3</sup>), and JEI. The full text of published letters will also be freely available for downloading from the online journal, without a subscription. For submission guidelines, please see the Information for Contributors published in this issue, or visit the JEI website at <http://spie.org/jei/>. We look forward to receiving submissions of your most significant and noteworthy work for consideration in JEI Letters.